

Notice of References Cited	Application/Control No. 09/929,708	Applicant(s)/Patent Under Reexamination NISHIKI, HIROHIKO	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,191,007	02-2001	Matsui et al	438/459
	B	US-6,545,410	04-2003	Wu et al	313/582
	C	US-6,104,457	08-2000	Izumi et al	349/73
	D	US-2003/0082326	05-2003	Yang et al	428/40.1
	E	US-5,838,405	11-1998	Izumi et al	349/73
	F	US-5,428,190	06-1995	Stopperan	174/261
	G	US-6,521,511	02-2003	Inoue et al	438/458
	H	US-6,572,941	06-2003	Murakami et al	428/34
	I	US-5,670,843	09-1997	Matsuura	313/582
	J	US-6,612,888	09-2003	Pai et al	445/24
	K	US-2002/0196386	12-2002	Grace et al	349/61
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 185 998	12-1985	European	Bakewell	
	O	JP 9-243982	09-1997	Japan		
	P	JP 8-160439	06-1996	Japan		
	Q	JP 9-160005	06-1997	Japan	Kanbe	
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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